

# VEO\_JM DIAMOND 2.5 × / F2.6

For TDI Line Scan

## Key Features

- Optimized for 82 mm line scan sensors
- High resolution over the entire field
- Resolves 2.5  $\mu\text{m}$  in object space
- With beam splitter for axial in-line illumination
- Low chromatic focal shift
- No relative illumination loss at the edge
- Best azimuth marking

## Applications

- FPD (OLED / LCD) inspection
- PCB inspection
- High resolution defect detection
- Quality assurance systems

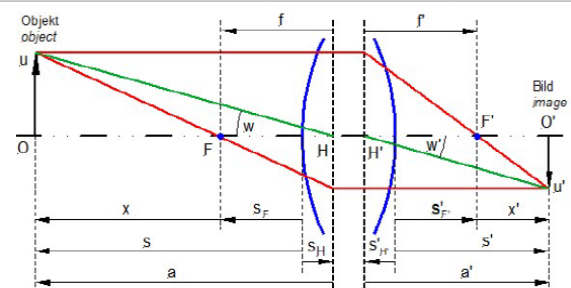


## Performance

Parameter	Specification	Remarks
Magnification range	2.5 (2.4 ... 2.6)	
F/# range	F/2.6 ... F/5.6	Optimum F/2.6
Numerical aperture	0.134	
Max. sensor size [mm]	82	
Infinite F/#	F/2.6	
Focal length [mm]	119	
Depth of field [ $\mu\text{m}$ ]	29.2	@ P. CoC 10 $\mu\text{m}$
Distortion	< 0.05%	
Wavelength [nm]	400 ... 700	Visible
Working distance [mm]	59.2 (60 ... 58)	B/S ... Object
Beam splitter size	25 × 25 × 80	
Total length [mm]	570.4 ± 2	from Object to Sensor
Interface	V90 mount	0.75 pitch
Iris	Changeable	
Relative illumination	Less than 5%	
Weight [g]	1510	

## Optical Parameters

Contents	Parameter	Value
Chief Ray Angle (Max.) in object plane	CRA	5.6°
Effective focal length	f'eff [mm]	119.7
Front focal length	SF [mm]	-12.39
Back focal length	S'F' [mm]	67.10
Principal plane distance	HH' [mm]	-16.55
Pupil magnification	$\beta'P$	1.0
Entrance pupil position	SEP [mm]	106.80
Exit pupil position	S'AP [mm]	-53.11
Vertex width	$\Sigma d$ [mm]	143.36



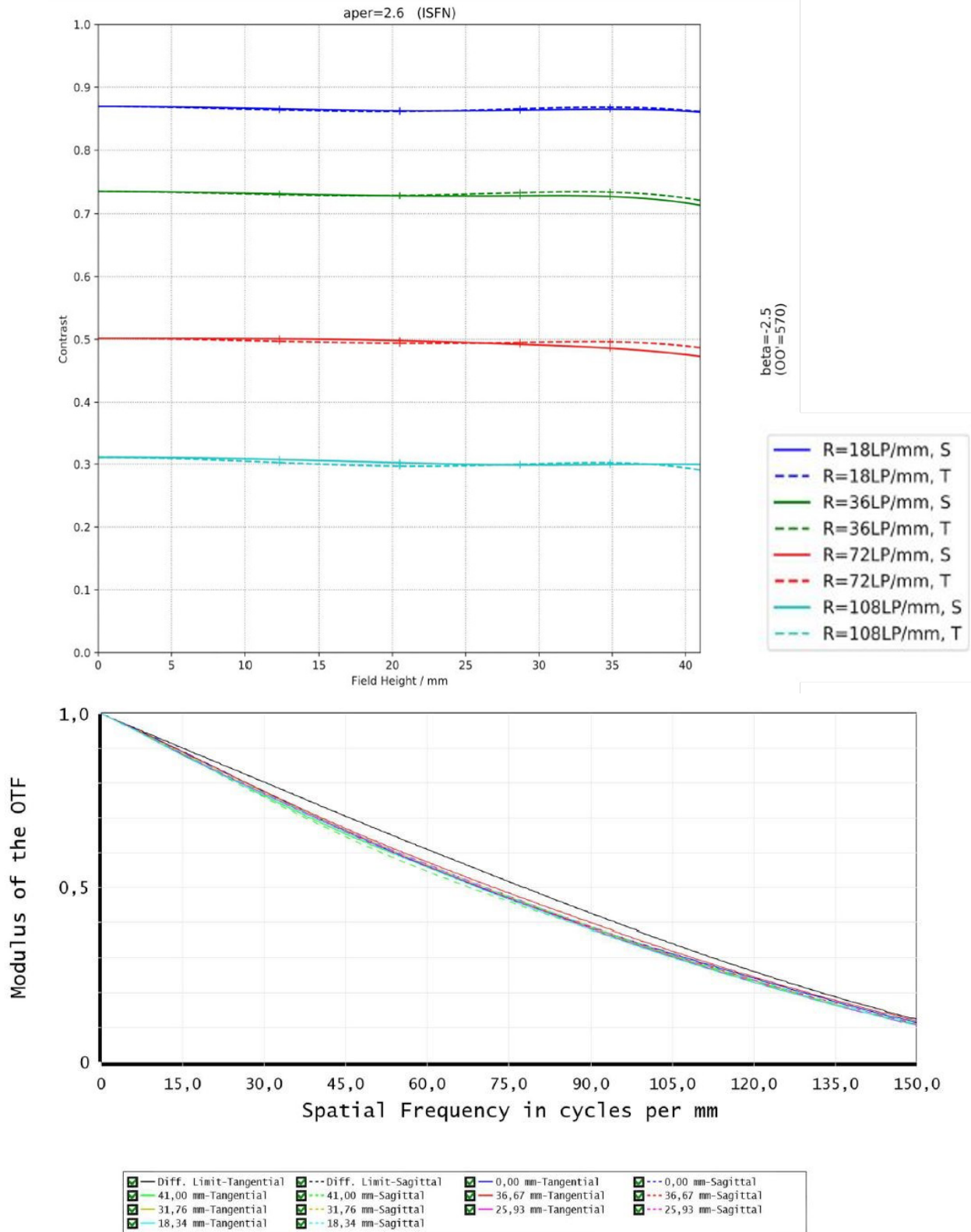
**VIEWWORKS**

www.vieworks.com

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## MTF



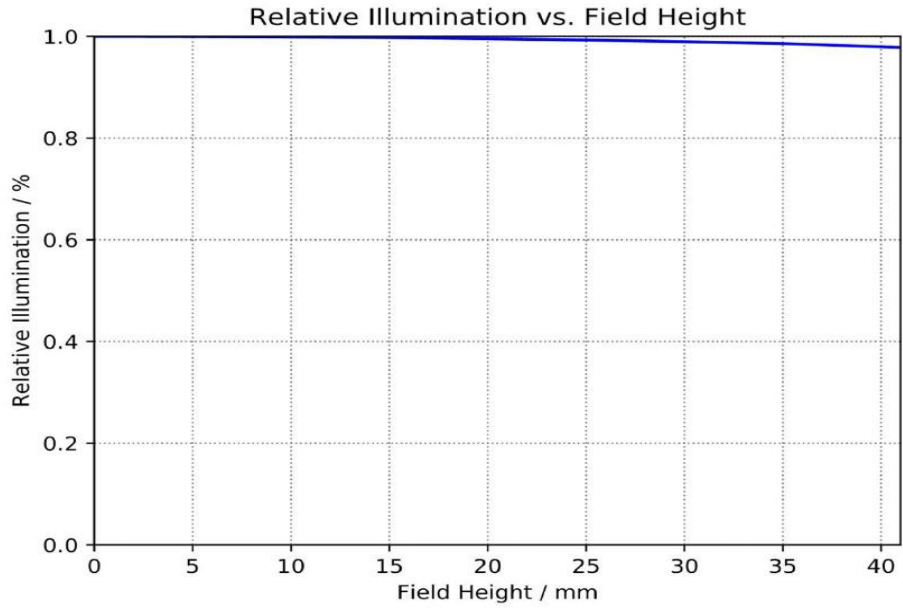
### Polychromatic Diffraction MTF

Data for 0.4360 to 0.6450  $\mu\text{m}$

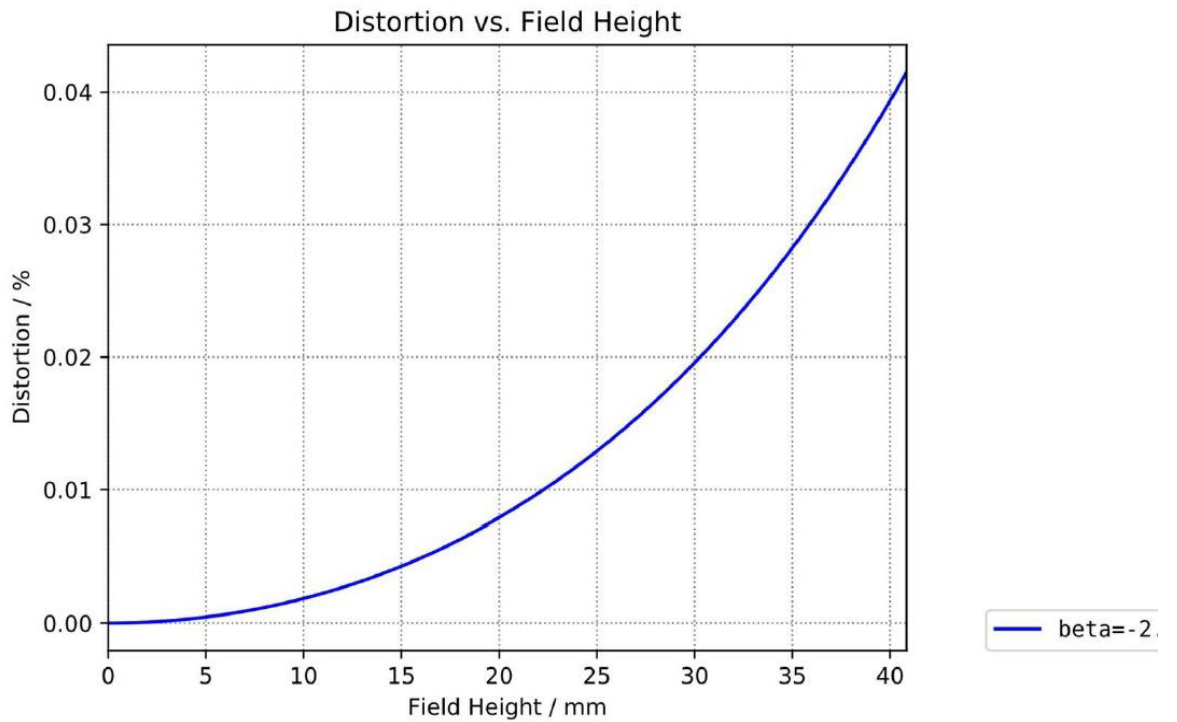
Surface: Image (image level)

Legend items refer to Field positions

## Relative Illumination



## Distortion



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## Dimensions

Unit: mm

